

# Photon Energy Calibration Systematics

Christophe Goudet



January 18, 2017

# Model Comparison

Two correlation models of systematics are proposed :

- FULL model decorrelate all NP.
- ALL model sum in quadrature respectively all systematic sources into respectively a single nuisance parameter for scale and resolution.
- The fit with  $m_{\gamma\gamma} \in [115, 135]\text{GeV}$  is used as closest to the signal model tool default behaviour.
- Major (surprising?) difference for scale uncertainty

Total Inclusive Uncertainty :		
%	Scale	Resolution
FULL	0.27	8.26
ALL	0.46	9.02

# Exact uncertainty

(Thanks Guillaume for explanation)

- Consider  $N_{NP}$  NP with constant values  $N_B$  bins (in  $\eta$ ,  $p_T$ , conversion status).
- The covariance matrix  $V$  is then defined as :

$$V_{ij} = \sum_n^{N_{NP}} \sigma_{n,i} \sigma_{n,j} \quad (1)$$

- The total inclusive uncertainty on measured mass is then,

$$\frac{\sigma_M}{M} = \frac{1}{N_\gamma} \sqrt{\sum_{ij}^{N_B} N_i N_j V_{ij}} \quad (2)$$

$N_i$  = number of photons in bin  $i$ ,

# Models total mass uncertainty

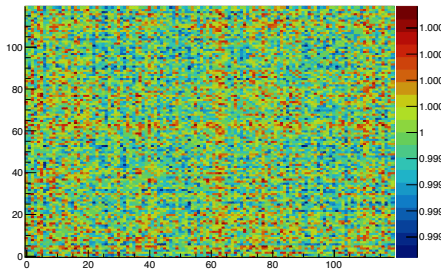
(Thanks Guillaume for cross-check)

ALL

FULL

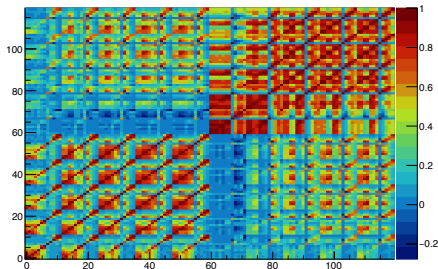
Correlation matrix

Corr matrix



$$\frac{\sigma_M}{M} = 0.47\%$$

Corr matrix



$$\frac{\sigma_M}{M} = 0.26\%$$

Cross-checks validate values obtained by mass fitting.

## Category comparison

The previous inclusive results are compared to asimov with 13 categories.

Total Scale Uncertainty :			
%	ALL	FULL	ratio
Mass fit	0.46	0.27	41
Formula	0.47	0.26	45
Asimov	0.53	0.34	36

Bad calibration categories have a higher contribution to the resolution.

# Photon Energy Calibration Systematics

Christophe Goudet



January 18, 2017

# Systematics in statistical framework

Changing an energy correction factor (by systematic fluctuation) affects several parameters. For current results, it is assumed that **only the parameter  $X$  targetted by the systematic (POI) is affected** (hence fixing the others).

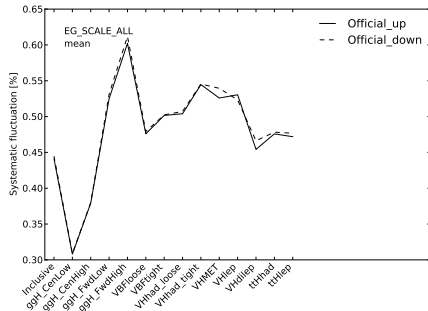
Only the parametrization of  $X$  will contain the measured uncertainty  $\delta_X$  :

$$X \rightarrow X(1 + \delta_X \theta)$$

with  $\theta$  a gaussian constrained free parameter.

In the framework, the pulling of the nuisance parameters only affects the main parameter of the systematic

# Typical plot



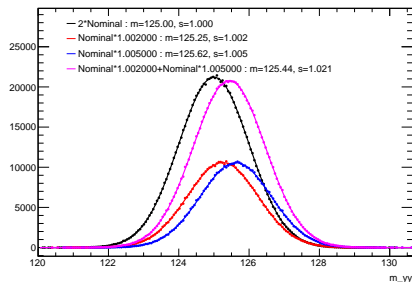
For a given fitted variable (here mean) :

- Full line :  $\frac{\mu_{up} - \mu_{nominal}}{\mu_{nominal}}$
- Dashed line :  $-\frac{\mu_{down} - \mu_{nominal}}{\mu_{nominal}}$

Both lines should be superimposed in case of symmetric systematics.



# Scale impact on width

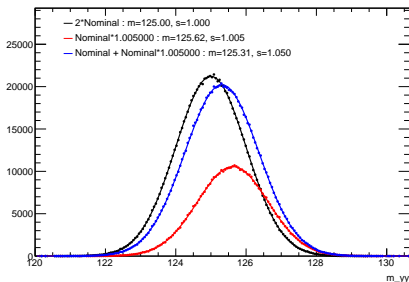


1M random numbers generated on a Gaussian( $\mu = 125, \sigma = 1$ ).

- Initial numbers distribution.
- Half events multiplied by 1.002.
- Remaining events multiplied by 1.005.
- Combined distribution of red and blue.

Mean (m) and RMS (s) of a fitted gaussians are given in the legend.  
Interpretation of the curve in the next slides.

# Uncertainty reduction



Lets assume a gaussian distributed energy distribution. Events are affected **either** by systematic A or B with same amplitude (0.3%).

Summing quadratically the systematic gives  $\delta E = 0.3\%$  for all event. Hence  $\Delta M = 0.3\%$ .

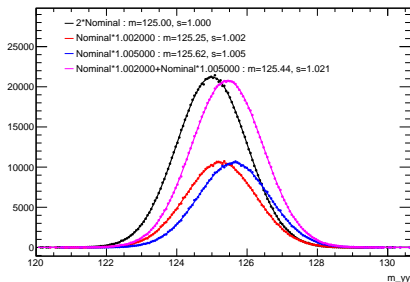
Applying independently systematics to events gives :

$$\Delta M_A = \Delta M_B = \delta E/2$$

Because only half events are effectively modified. Finally :

$$\Delta M = \Delta M_A \oplus \Delta M_B = \frac{\delta E}{\sqrt{2}}$$

## $\mu/\sigma$ scale correlation



Lets assume a gaussian distributed energy distribution. Applying energy scale correction gives :

$$E \rightarrow E(1 + a)$$

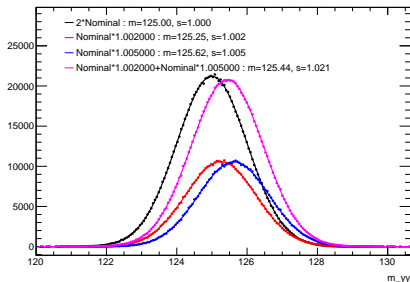
Hence the distribution will be changed to :

$$\exp\left(-\frac{(E - \mu)^2}{2\sigma^2}\right) \rightarrow \exp\left(-\frac{\left(\frac{E}{1+a} - \mu\right)^2}{2\sigma^2}\right) = \exp\left(-\frac{(E - \mu(1 + a))^2}{2\sigma^2(1 + a)^2}\right) \quad (3)$$

The new distribution is a **shifted gaussian with scaled RMS**.

Given the medium shift of EG\_SCALE\_ALL, we expect  $\begin{smallmatrix} +0.4\% \\ -0.4\% \end{smallmatrix}$  change in resolution.

# Inhomegenous scale



The RMS of two points separated by  $d$  is  $d/4$ .

If  $d$  is the difference between two scale factors,

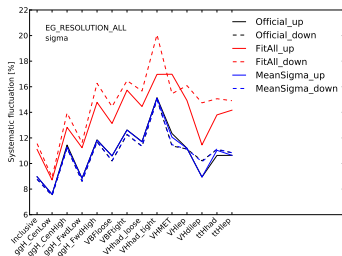
$$d \sim 3 \cdot 10^{-3} \cdot E_\gamma = 0.18$$

$$\frac{\text{RMS}}{\text{Resolution}} = \frac{d/4}{1.5\text{GeV}} = 3\%$$

The inhomogeneity of the scale factors uncertainties **changes the width of the distribution at the percent level**. This effect will always increase the width.

Black and pink distribution show an illustration of this effect.

# Fitting methods : $\sigma$ fluctuation

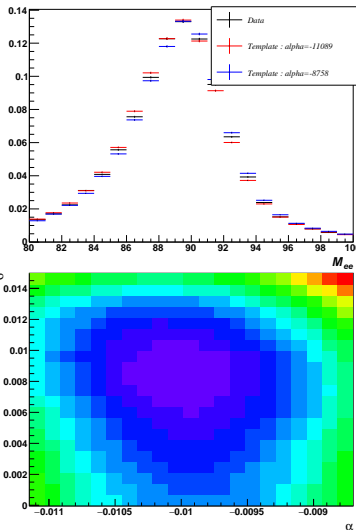
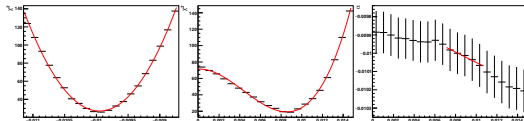


- $\sigma$  is sensitive to the change of scale.
- Two understood explanations :
  - ▶  $\mu/\sigma$  correlation when scaling energies.
  - ▶ Resolution loss due to inhomogenous scaling.
- Effect on resolution is small but I propose to **add a width effect linked to EG\_SCALE\_ALL nuisance parameter.**
  - ▶ Add a second nuisance parameter to the width to limit overconstraints.
  - ▶ Good hopes to reduce Zee resolution systematics (dominant in EG\_RESOLUTION\_ALL) within medium timescale.

## Cross-check : template method

The template method is used to measure  $\alpha$  and  $C$  simultaneously.

- Create distorted MC (templates) with test values of  $\alpha$  and  $C$ .
- **Compute  $\chi^2$  between Z mass distribution of data and template.**
- **Fit the minimum of the  $\chi^2$  distribution** in the  $(\alpha, C)$  plane.
- Fit performed in 2 steps of 1D fits :
  - ▶ fit  $\chi^2 = f(\alpha)$  at constant  $C$  (lines)  $\rightarrow (\alpha_{min}, \chi^2_{min})$ .
  - ▶ fit  $\chi^2_{min} = f(C) \rightarrow (C, \Delta C)$
  - ▶ project  $C$  in  $\alpha_{min} = f(C)$ , corresponding bin gives  $(\alpha, \Delta\alpha)$ .



# Scale factors interpretation

Assume the up fluctuation (red) as data and nominal distribution (black) as MC in the template method. One has

$$m_H^{up} = m_H^{nom}(1 + \alpha)$$

Hence

$$\delta_{m_H} = \alpha$$

Furthermore :

$$\sigma_H^{up} = \sigma_H^{nom} \oplus cE$$

Hence

$$\delta_{\sigma_H} = \sqrt{1 + \frac{c^2 E^2}{\sigma_H^2}} - 1$$

One has to be careful with resolution uncertainty as the template method is weak to measure small differences.

